


<b>Search Notes</b>  	<b>Application/Control No.</b>  10595627	<b>Applicant(s)/Patent Under Reexamination</b>  NAKAMURA ET AL.
	<b>Examiner</b>  Thuy N Pardo	<b>Art Unit</b>  2627

SEARCHED			
Class	Subclass	Date	Examiner
369	30.04, 30.07, 30.09, 59.25, 53.27, 03.07	4/29/2009	TP
711	5	4/29/2009	TP
707	3	11/20/2009	TP
369	47.11, 53.18	11/20/2009	TP
369	59.25, 47.19, 53.16, 44.28, 13.06, 47.1, 53.21	3/24/2010	TP
711	202	3/24/2010	TP
360	49, 78.04	3/24/2010	TP

SEARCH NOTES		
Search Notes	Date	Examiner
WEST	4/29/2009	TP
WEST	11/20/2009	TP
WEST, NPL: Google Scholar, ACM	3/24/2010	TP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
369	59.25, 47.19, 53.16, 44.28, 13.06, 47.1, 53.21, 47.11, 53.18	3/24/2010	TP
711	5, 202	3/24/2010	TP
707	3	3/24/2010	TP
360	49, 78.04	3/24/2010	TP

	/Thuy N Pardo/ Primary Examiner.Art Unit 2627
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